INTERNATIONAL CENTRE FOR DIFFRACTION DATA

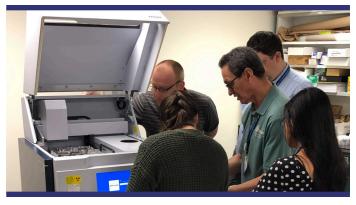


Techniques & Skills to Maximize Results!



- Fundamentals of X-ray Physics
- WDX and EDX X-ray spectrometry instrumentation
- Qualitative, semi-quantitative and standardless analysis
- Introduction to quantitative analysis
- Types and sources of error
- Precision and accuracy
- Calibration strategy
- Drift, line and interelement correction application
- Fundamental parameters
- Maintaining instrument integrity
- Specimen preparation

CUTTING-EDGE EQUIPMENT DEMONSTRATIONS



TXRF • HANDHELD XRF • FUSIONS



XRF instrumentation, components, scope, and comparison

- using live and disabled WDX and EDX instrumentation
- Selection of parameters for operation
- Hands-on computer exercises in qualitative, semi-qualitative and standardless WDX and EDX analysis
- Hands-on computer exercises employing polynomial regression, line overlap, empirical and fundamental parameter correction during calibration
- Specimen preparation lecture and demonstration of the use of mixers, grinders, presses, fusion apparatus, etc.
- Discussion of problems encountered by participants

Please note: A minimum of 10 registrants per course is required, otherwise the course will be cancelled and your registration fee will be refunded. You will be notified of a course cancellation no later than two weeks prior to the start of the course.

Contact: Elizabeth Dempsey

12 Campus Boulevard • Newtown Square, PA 19073 USA Phone: +610.325.9814 • Toll-free (U.S. & Canada) 866.378.9331 Fax: +610.325.9823 • Web: www.icdd.com • Email: clinics@icdd.com



ICDD, the ICDD logo, PDF, Materials Data, JADE, Denver X-ray Conference, Denver X-ray Conference logo, and Materials Data-JADE-SM-WPF logo are registered in the U.S. Patent and Trademark Office. Powder Diffraction File, MDI, and the MDI-Materials Data logo are trademarks of the JCPDS-International Centre for Diffraction Data. ©2023 JCPDS-International Centre for Diffraction Data. Rev. 7/23

www.icdd.com/xrf